

Using the PIC[®] MCU CTMU for Temperature Measurement

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The Charge Time Measurement Unit (CTMU), introduced on the latest generation of PIC24F and PIC18F devices, uses a constant current source to calculate both capacitance changes and the time difference between events. The same current source can also be used to measure temperature by exploiting a basic principle of semiconductor physics. This allows the use of a common and inexpensive diode, in the place of a relatively more expensive thermistor or other temperature sensor. This brief describes the basic concepts of temperature measurement using the CTMU.

BASIC PRINCIPLE

We can show that the forward voltage (V_F) of a P-N junction, such as a diode, is an extension of the equation for the junction's thermal voltage:

$$V_F = \frac{kT}{q} \ln\left(1 + \frac{I_F}{I_S}\right)$$

where k is the Boltzmann constant ($1.38 \times 10^{-23} \text{ J K}^{-1}$), T is the absolute junction temperature in kelvin, q is the electron charge ($1.6 \times 10^{-19} \text{ C}$), I_F is the forward current applied to the diode, and I_S is the diode's characteristic saturation current.

Since k and q are physical constants, and I_S is a constant for the device, this only leaves T and I_F as independent variables. If I_F is held constant, it follows from the equation that V_F will vary as a function of T . As the natural log term of the equation will always be negative, the temperature will be negatively proportional to V_F . In other words, as temperature increases, V_F decreases.

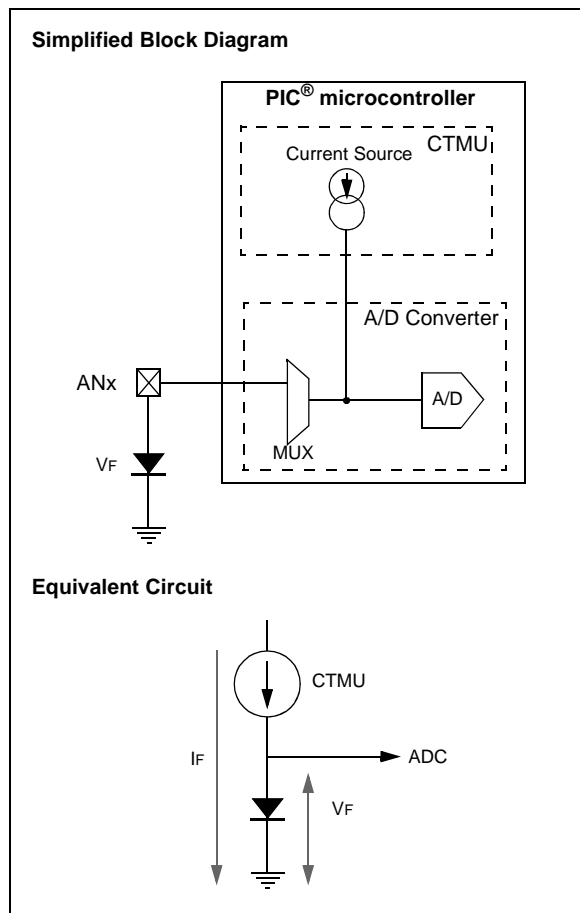
By using the CTMU's current source to provide a constant I_F , it becomes possible to calculate the temperature by measuring the V_F across the diode.

IMPLEMENTATION

To implement this theory, all that is needed is to connect a regular junction diode to one of the microcontroller's A/D pins (Figure 1). The A/D channel multiplexer is shared by the CTMU and the ADC.

To perform a measurement, the multiplexer is configured to select the pin connected to the diode. The CTMU current source is then turned on, and an A/D conversion is performed on the channel. As shown in the equivalent circuit diagram, the diode is driven by the CTMU at I_F . The resulting V_F across the diode is measured by the ADC.

FIGURE 1: CTMU TEMPERATURE MEASUREMENT CIRCUIT



EXPERIMENTAL VALIDATION

To test the theory, several devices with simple P-N junctions were tested in a controlled temperature environment while measuring V_F as previously described. Included in the testing were three common silicon diodes, two common bipolar transistors, and two LEDs. An additional trial was run with two diodes (1N914) connected in parallel as a single unit. Each device was evaluated using an ADC voltage reference (V_{REF}) of 3.3V.

Temperature was varied from 0°C to 105°C inclusive, with 256 conversions being taken at roughly 5°C intervals over this range. The ADC readings (proportional to voltage) were recorded for each temperature point. These readings were used to directly calculate resolution, and converted to voltage to calculate line slope.

Resolution (expressed as temperature per ADC counts) is calculated as:

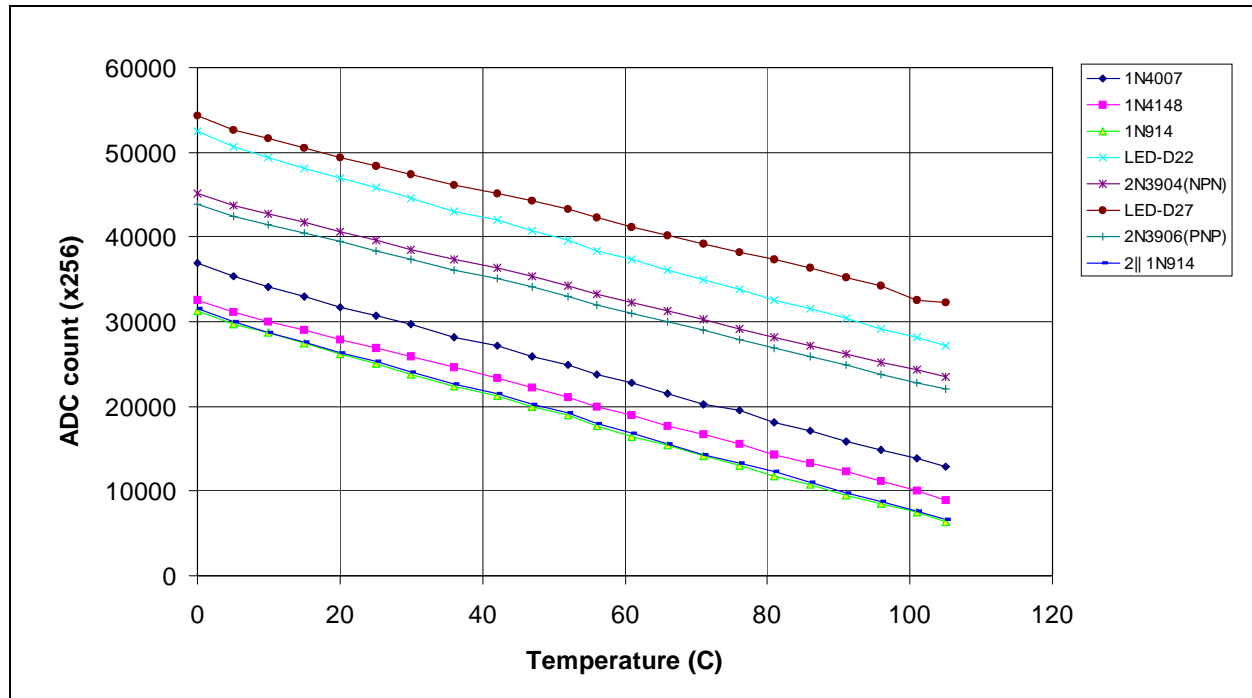
$$\frac{\text{Number of samples} \times \text{Temperature range}}{\text{Counts at min temperature} - \text{Counts at max temperature}}$$

The results of the trial are summarized in Table 1, and presented in graphic form in Figure 2. As can be seen, the correlation between temperature and V_F is negative. Also as expected, the relationship between temperature and the forward voltage on the junction is essentially linear. This makes it possible for any readily available diode – or for that matter, any inexpensive semiconductor – to function as a low-resolution temperature sensor in conjunction with the CTMU.

TABLE 1: EXPERIMENTAL V_F VALUES (AS ADC COUNTS) FOR DIFFERENT DEVICES AS A FUNCTION OF TEMPERATURE

Component	ADC Readings (256 samples)		Resolution (°C/Count)	Slope
	Min. Temp	Max. Temp		
1N4007	36,890	12,815	1.12	-2.88 mV/°C
1N4148	32,500	8,980	1.15	-2.8 mV/°C
1N914	31,500	6,417	1.08	-2.98 mV/°C
2N3904 (NPN)	45,100	23,560	1.26	-2.56 mV/°C
2N3906 (PNP)	43,860	22,020	1.24	-2.60 mV/°C
SML-LXT0805GW-TR (Green LED)	52,500	27,150	1.07	-3.01 mV/°C
CML 5311F (Red LED)	54,280	32,265	1.23	-2.62 mV/°C
Two 1N914 (parallel)	31,500	6,660	1.09	-2.95 mV/°C

FIGURE 2: ADC VALUES AS A FUNCTION OF TEMPERATURE FOR TESTED DEVICES



INCREASING TEMPERATURE MEASUREMENT RESOLUTION

The method described here is adequate for resolution of about 1°C. In most cases, this represents an A/D channel voltage change of about 3 mV. At this scale, attempts to get better resolution will run into the limitations of the A/D converter. To achieve higher temperature resolutions, some minor changes to the conversion method are needed. These include:

- Using a lower reference voltage for the ADC. One significant determining factor in temperature resolution is the selection of VREF. Smaller values of VREF tend to produce a larger difference voltage to be converted; this produces a larger incremental reading per degree, and thus higher resolution. Table 2 shows the expected temperature resolution for the same experiment, assuming an ADC VREF of 2.0V.
- Using two diodes in series. Although this does not increase resolution *per se*, the resulting doubling of the change in the measured voltage per unit of temperature will result in increased accuracy.
- Adding a single stage of voltage amplification with an op amp. By increasing the voltage to the ADC and matching it to the ADC voltage reference, resolution is increased. Although this adds several external components and some cost to the solution, this may be desirable in applications where a more precise determination of temperature is required.

TABLE 2: EXPECTED TEMPERATURE RESOLUTION FOR VREF OF 2.0V

Component	Resolution (°C/Count)	
	VREF = 3.3V (observed)	VREF = 2.0V (predicted)
1N4007	1.12	0.68
1N4148	1.15	0.69
1N914	1.08	0.66
2N3904	1.26	0.76
2N3906	1.24	0.75
SML-LXT0805GW-TR	1.07	0.64
CML 5311F	1.23	0.74
Two 1N914 (parallel)	1.09	0.66

CONCLUSION

For applications using a PIC18F or PIC24F microcontroller with the CTMU, adding a temperature function does not depend on the use of a special temperature sensor; it can be done using a commodity diode and a small addition of code to the application firmware. This makes the incremental cost of adding the additional feature very small indeed.

REFERENCES

PIC24F Family Reference Manual, Section 11, "*Charge Time Measurement Unit (CTMU)*" (DS39724). Microchip Technology Inc., 2008.

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